## Application/Control No. O9/593,956 Applicant(s)/Patent Under Reexamination TOKIWA ET AL. Examiner Samuel P Siefke Applicant(s)/Patent Under Reexamination TOKIWA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,080,364	06-2000	Mimura et al.	422/67
	В	US-			
	С	US-			
	D	US-			
•	E	US-			
	F	US-			
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	J	US-			
	К	US-			
	L	US-			
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## **NON-PATENT DOCUMENTS**

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